AMENDMENTS TO THE CLAIMS

1. (Original) An electronic device testing apparatus for conducting a test by pressing input/output terminals of electronic devices to be tested against contact portions of a test head using a moving means while holding said electronic devices to be tested on an electronic device conveying medium, comprising:

a test head provided with a plurality of contact groups made by a set of contact portions; and

a moving means capable of independently controlling said electronic device conveying medium loaded with said electronic devices to be tested to said contact groups.

2. (Original) The electronic device testing apparatus as set forth in claim 1, wherein said electronic device conveying medium loaded with said electronic devices to be tested is a strip format or a wafer.

3. (Currently Amended) The electronic device testing apparatus as set forth in claim 1 ~~or~~ 2, comprising a control means for finishing tests with the shortest time on remaining said electronic devices to be tested on said electronic device conveying medium when a lot of said electronic devices to be tested finishes.

4. (Original) The electronic device testing apparatus as set forth in claim 3, wherein in the case where said electronic device conveying medium loaded with said electronic devices to be tested is already on said contact group when a lot of said electronic devices to be tested finishes,

said control means suspends a test on said electronic devices to be tested already under the test in said contact group and outputs an instruction to move said electronic device conveying medium loaded with said electronic devices to be tested to other contact group already finished with tests and having a large number of contact portions.

5. (Currently Amended) The electronic device testing apparatus as set forth in claim 3 [[or 4]], wherein said control means outputs an instruction for determining to which contact group said electronic device conveying medium loaded with remaining said electronic devices to be tested yet to be supplied to any contact group when a lot of said electronic devices to be tested finishes should be supplied, based on the number of electronic devices to be tested on said electronic device conveying medium, the number of contact portions in respective contact groups, and standby time until a test.

6. (Original) The electronic device testing apparatus as set forth in any one of claims 1 to 5, wherein each of said moving means moves by gripping said electronic device conveying medium loaded with said electronic devices to be tested from a loading position of pre-test electronic devices to a corresponding contact group.

7. (Currently Amended) The electronic device testing apparatus as set forth in any one of claims ~~1 to 6~~ 1 to 5, wherein each of said moving means moves by gripping said electronic device conveying medium loaded with said electronic devices to be tested from said corresponding contact group to a loading position of post-test electronic devices.

8. (Currently Amended) The electronic device testing apparatus as set forth in any one of claims ~~1 to 7~~ 1 to 5, wherein a sum of the numbers of contact portions composing said plurality of contact groups in said test head is 2^n ("n" is a natural number).

9. (Original) The electronic device testing apparatus as set forth in claim 8, wherein n=5.

10. (Original) The electronic device testing apparatus as set forth in claim 8, wherein n=6.

11. (Original) An electronic device testing method, wherein a test head is provided with a plurality of contact groups made by sets of contact portions; for conducting a test by moving a plurality of electronic device conveying media loaded with electronic devices to be tested at a time and pressing input/output terminals of said electronic devices to be tested against contact portions of the test head; wherein

one of said electronic device conveying media is moved independently from other electronic device conveying media to a corresponding contact group.

12. (Original) The electronic device testing method as set forth in claim 11, wherein tests on remaining said electronic devices to be tested on said electronic device conveying media are finished with the shortest time when a lot of said electronic devices to be tested finishes.

13. (Original) The electronic device testing method as set forth in claim 12, wherein in the case where said electronic device conveying medium loaded with said electronic devices to be tested is already on said contact group when a lot of said electronic devices to be tested finishes, a test on said electronic devices to be tested already under the test in said contact group is suspended, and said electronic device conveying medium loaded with said electronic devices to be tested are moved to other contact group already finished with tests and having a large number of contact portions.

14. (Currently Amended) The electronic device testing method as set forth in claim 12 ~~or~~ ~~13~~, for outputting an instruction for determining to which contact group said electronic device conveying medium loaded with remaining said electronic devices to be tested yet to be supplied to any contact group when a lot of said electronic devices finishes should be supplied, based on the number of electronic devices to be tested on said electronic device conveying medium, the number of contact portions in respective contact groups, and standby time until a test.

15. (Original) The electronic device testing method as set forth in any one of claims 11 to 14, wherein a sum of the numbers of contact portions composing said plurality of contact groups in said test head is 2^n ("n" is a natural number).

16. (Original) The electronic device testing apparatus as set forth in claim 15, wherein n=5.

17. (Original) The electronic device testing apparatus as set forth in claim 15, wherein n=6.